

10) M Series Basics Manual Probe Station



Product Overview

A Basics type based on the university education and laboratory test wafer prober, this equipment is mainly applied in the semiconductor industry, as well as test of the photoelectric industry, including research and development of precision electrical measurement of complex high-speed device, the chip and LD/LED/PD tests, PCB/packaging device testing, rf testing 50 microns electrode/PAD test materials/components/CV IV characteristic test, etc.

Basic Information

Product number	M4、M6、M8	working environment	Open type
electricity demand	220V,50~60Hz	Control method	Manual probe station
Product Size	M4、M6: 650*490*620mm M8: 766*500*651mm	equipment weight	M4: about 45kg M6: about 52kg M8: about 90kg

Application direction

This equipment is mainly used for testing in semiconductor and optoelectronic industries, including r&d chip and LD/LED/PD test of complex high-speed devices, PCB/ package device test, AND IV/CV characteristic test of electrode /PAD test material/device over 50 microns.

Technical characteristics